Application No.: 09/867,766

AMENDMENT TO CLAIMS

Please amend the claims as follows:

- 1. (Currently amended) A semiconductor integrated circuit comprising:
- a ROM for storing plural confidential data thereon address by address which has no external direct input path and can be read only from an internal circuit inside of the integrated circuit;
 - a tester for testing the ROM address by address; [[and]]
- a storage device, which is included in the ROM, for storing plural redundancy check data address by address that have been obtained by performing a predetermined calculation on each of the corresponding plural confidential data, the plural redundancy check data and each of the corresponding plural confidential data being stored at mutually different addresses on the ROM;

wherein the tester includes a checker for performing the same calculation as the predetermined calculation on each of the plural confidential data that has been read out from the ROM address by address[[,]];

[[wherein]] a comparator for comparing a result of the calculation performed by the checker is compared to each of the corresponding plural redundancy check data stored in the storage device address by address[[,]]; and

an address decoder which enables an operation of the comparator if the address is for the redundancy check data, and disables the operation of the comparator if the address is for the confidential data.

wherein the storage device is included in the ROM, and

wherein the plural redundancy check data and each of the corresponding plural confidential data are stored at mutually different addresses on the ROM.

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2-4. (Cancelled)

- 5. (Currently amended) A method of testing a semiconductor integrated circuit including a ROM that stores plural confidential data thereon address by address and which can be read only from an internal circuit inside of the integrated circuit, the method comprising the steps of:
- a) storing plural redundancy check data, which have been obtained by performing a predetermined calculation on each of the corresponding plural confidential data, in a redundancy check data storage device of the integrated circuit included in the ROM;
- b) reading out each of the plural confidential data from the ROM address by address and performing the same calculation as the predetermined calculation on each of the plural confidential data read out; and
- c) reading out each of the corresponding plural redundancy check data from the storage device address by address and comparing a result of the calculation performed in the step b) to each of the corresponding plural redundancy check data read out.

wherein the storage device is included in the ROM, and

wherein the plural redundancy check data and each of the corresponding plural confidential data are stored at mutually different addresses on the ROM,

and the comparison is enabled if the address is for the redundancy check data, and disabled if the address is for the confidential data.